



P-Channel Enhancement-Mode Vertical DMOS Power FETs

Ordering Information

$BV_{DSS} /$ BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	DICE
-20V	4.0Ω	-0.85A	TP0102N2	TP0102N3	TP0102ND
-40V	4.0Ω	-0.85A	TP0104N2	TP0104N3	TP0104ND

Features

- ☐ Low threshold
- ☐ High input impedance
- ☐ Low input capacitance
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Freedom from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and negative temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

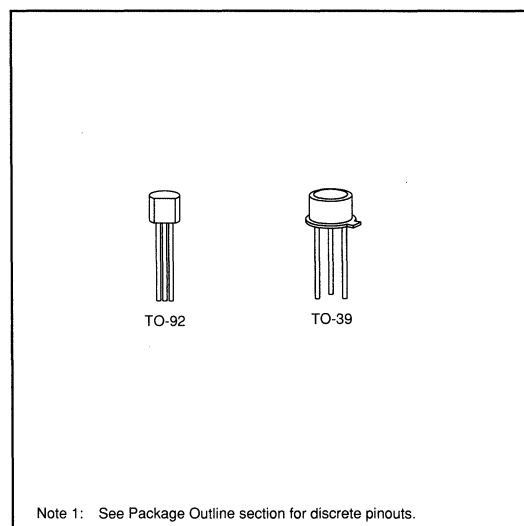
Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Applications

- ☐ Logic level interface
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switch
- ☐ General purpose line driver

Package Options

(Note 1)



Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

*Distance of 1.6 mm from case for 10 seconds.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)*	Power Dissipation @ $T_C = 25^\circ\text{C}$	θ_{JC} $^\circ\text{C/W}$	θ_{JA} $^\circ\text{C/W}$	I_{DR}	I_{DRM}^*
TO-39	-0.9A	-2.6A	3.5W	35	125	-0.9A	-2.6A
TO-92	-0.5A	-2.4A	1.0W	125	170	-0.5A	-2.4A

* I_D (continuous) is limited by max rated T_J .

Electrical Characteristics (@ 25°C unless otherwise specified)

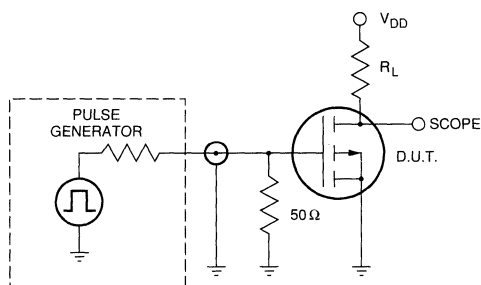
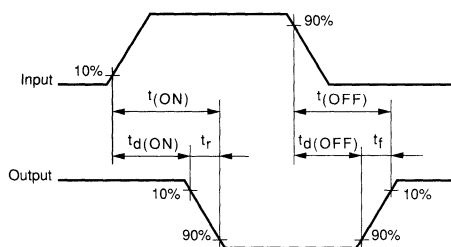
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP0104 -40 TP0102 -20			V	$V_{GS} = 0, I_D = -1.0\text{mA}$
$V_{GS(th)}$	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}, I_D = -1.0\text{mA}$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature		-5.8	-6.5	mV/ $^\circ\text{C}$	$V_{GS} = V_{DS}, I_D = -1.0\text{mA}$
I_{GSS}	Gate Body Leakage		-1.0	-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I_{DSS}	Zero Gate Voltage Drain Current			-10	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				-1	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current		0.08			$V_{GS} = -3\text{V}, V_{DS} = -25\text{V}$
		-0.25	-0.40		A	$V_{GS} = -5\text{V}, V_{DS} = -25\text{V}$
		-0.85	-1.70			$V_{GS} = -10\text{V}, V_{DS} = -25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		15			$V_{GS} = -3\text{V}, I_D = -25\text{mA}$
			5.5	7.5	Ω	$V_{GS} = -5\text{V}, I_D = -0.1\text{A}$
			2.5	4.0		$V_{GS} = -10\text{V}, I_D = -0.5\text{A}$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature		0.55	1.0	%/ $^\circ\text{C}$	$I_D = -0.5\text{A}, V_{GS} = -10\text{V}$
G_{FS}	Forward Transconductance	225	300		m Ω	$V_{DS} = -25\text{V}, I_D = -0.5\text{A}$
C_{ISS}	Input Capacitance		45	60		$V_{GS} = 0, V_{DS} = -25\text{V}$ $f = 1 \text{ MHz}$
C_{OSS}	Common Source Output Capacitance		22	30	pF	
C_{RSS}	Reverse Transfer Capacitance		3	8		
$t_{d(ON)}$	Turn-ON Delay Time		4	6	ns	$V_{DD} = -25\text{V}, I_D = -1\text{A}$ $R_S = 50\Omega$
t_r	Rise Time		7	10		
$t_{d(OFF)}$	Turn-OFF Delay Time		3	5		
t_f	Fall Time		4	6		
V_{SD}	Diode Forward Voltage Drop	-1.2	-2.0		V	$I_{SD} = -0.25\text{A}, V_{GS} = 0$
t_{rr}	Reverse Recovery Time		300		ns	$I_{SD} = -1.0\text{A}, V_{GS} = 0$

Note 1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300 μs pulse, 2% duty cycle.)

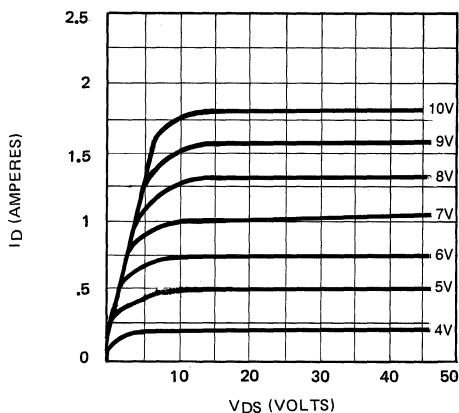
Note 2: All A.C. parameters sample tested.

Switching Waveforms and Test Circuit

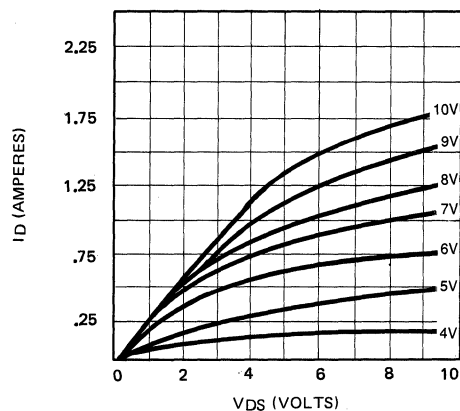


Typical Performance Curves

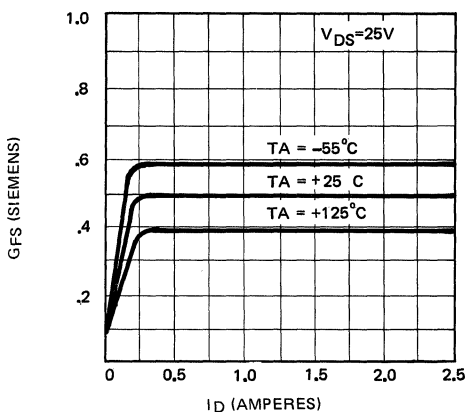
Output Characteristics



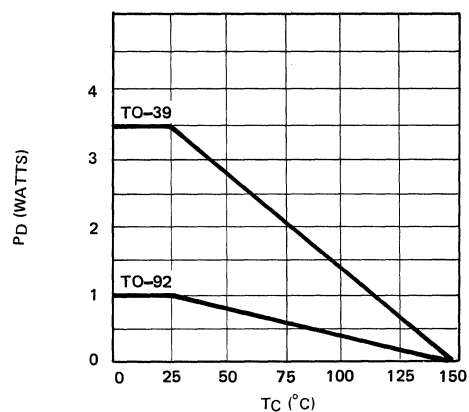
Saturation Characteristics



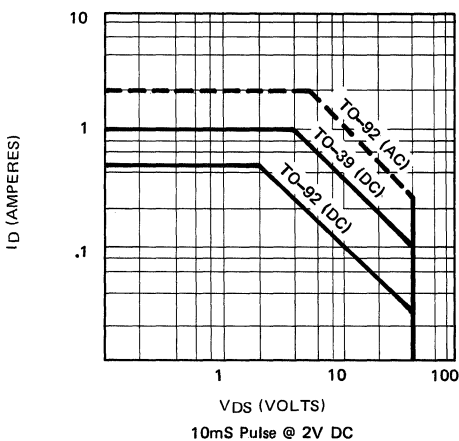
Transconductance Vs. Drain Current



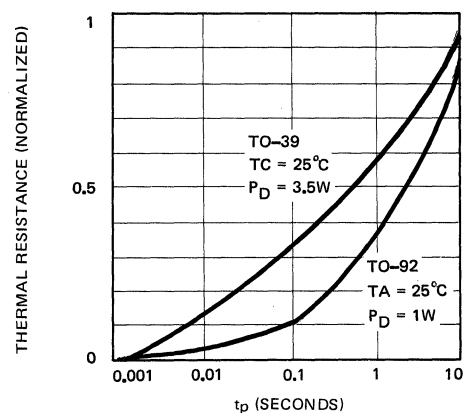
Power Dissipation Vs. Case Temperature



Maximum Rated Safe Operating Area



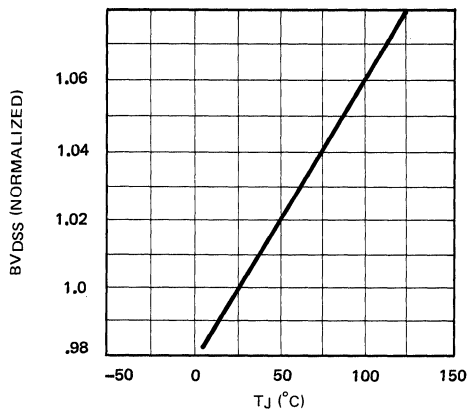
Thermal Response Characteristics



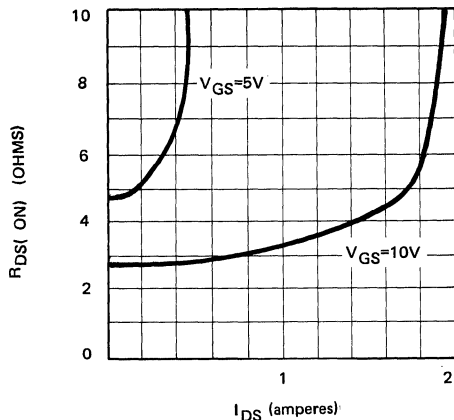
Typical Performance Curves

TP01L

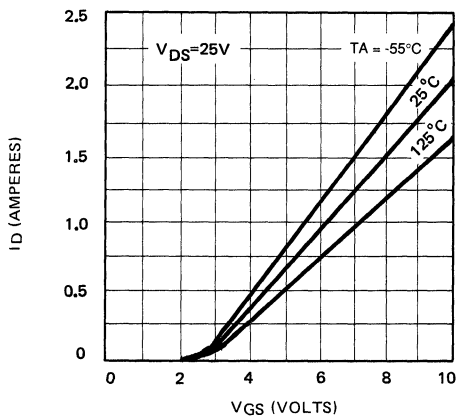
BVDSS Variation with Temperature



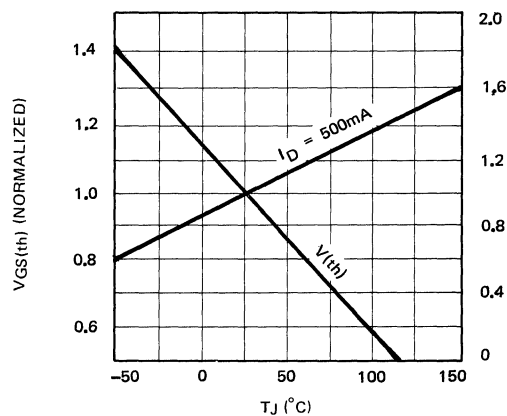
ON-Resistance Vs. Gate-to-Source Voltage



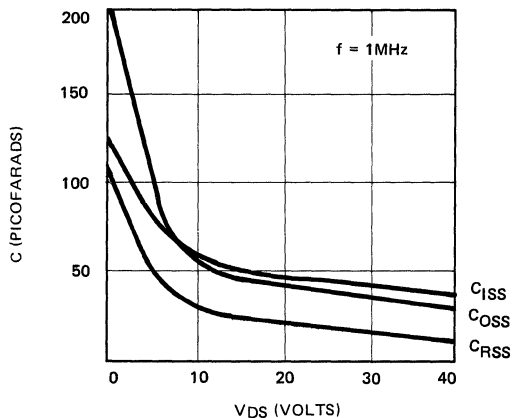
Transfer Characteristics



V(th) and RDS Variation with Temperature



Capacitance Vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics

